# 30V N-CHANNEL ENHANCEMENT MODE MOSFET

**SUMMARY** 

 $V_{(BR)DSS}$ =30V;  $R_{DS(ON)}$ =0.045 $\Omega$ ;  $I_D$ =5.0A

# **DESCRIPTION**

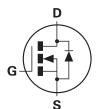
This new generation of high density MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.



#### MSOP8

#### **FEATURES**

- Low on-resistance
- · Fast switching speed
- Low threshold
- · Low gate drive
- Low profile SOIC package



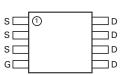
### **APPLICATIONS**

- DC DC converters
- Power management functions
- Disconnect switches
- Motor control



# **ORDERING INFORMATION**

DEVICE	REEL SIZE (inches)	TAPE WIDTH (mm)	QUANTITY PER REEL
ZXM64N03XTA	7	12 embossed	1,000
ZXM64N03XTC	13	12 embossed	4,000



Top view

# **DEVICE MARKING**

ZXM4P03



# **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V <sub>DSS</sub>	30	V
Gate- Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current $ \begin{array}{c} (V_{GS}{=}4.5V;T_A{=}25^{\circ}C)(b) \\ (V_{GS}{=}4.5V;T_A{=}70^{\circ}C)(b) \end{array} $	I <sub>D</sub>	5.0 4.0	А
Pulsed Drain Current (c)	I <sub>DM</sub>	30	А
Continuous Source Current (Body Diode)(b)	Is	2.4	А
Pulsed Source Current (Body Diode)(c)	I <sub>SM</sub>	30	Α
Power Dissipation at T <sub>A</sub> =25°C (a) Linear Derating Factor	P <sub>D</sub>	1.1 8.8	W mW/°C
Power Dissipation at T <sub>A</sub> =25°C (b) Linear Derating Factor	P <sub>D</sub>	1.8 14.4	W mW/°C
Operating and Storage Temperature Range	T <sub>j</sub> :T <sub>stg</sub>	-55 to +150	°C

### THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)	$R_{\theta JA}$	113	°C/W
Junction to Ambient (b)	$R_{\theta JA}$	70	°C/W

#### NOTES

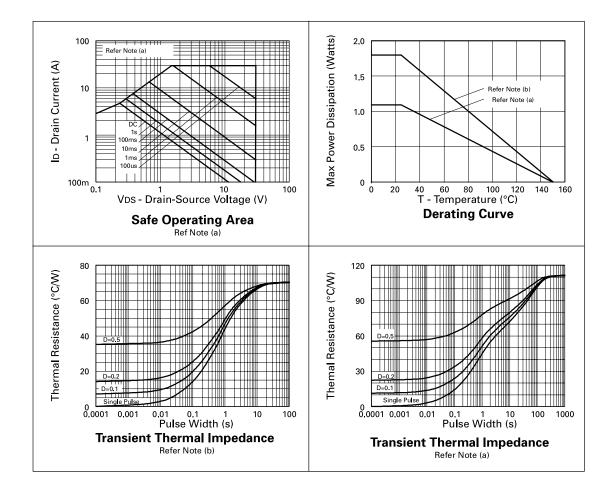
(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions

(c) Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.



<sup>(</sup>b) For a device surface mounted on FR4 PCB measured at t  $\leq$  10 secs.

### **CHARACTERISTICS**





# **ELECTRICAL CHARACTERISTICS** (at T<sub>amb</sub> = 25°C unless otherwise stated)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC	<u> </u>	•	•	•	•	•	
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	30			V	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			1	μА	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	
Gate-Body Leakage	I <sub>GSS</sub>			±100	nA	V <sub>GS</sub> =± 20V, V <sub>DS</sub> =0V	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1.0			V	$I_{D}^{=-250 \mu A}, V_{DS}^{=} V_{GS}$	
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.045 0.060	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =3.7A V <sub>GS</sub> =4.5V, I <sub>D</sub> =1.9A	
Forward Transconductance (3)	g <sub>fs</sub>	4.3			S	V <sub>DS</sub> =10V,I <sub>D</sub> =-1.9A	
DYNAMIC (3)		•	•	•	•	•	
Input Capacitance	C <sub>iss</sub>		950		pF		
Output Capacitance	C <sub>oss</sub>		200		pF	V <sub>DS</sub> =25 V, V <sub>GS</sub> =0V, f=1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>		50		pF		
SWITCHING(2) (3)	·						
Turn-On Delay Time	t <sub>d(on)</sub>		4.2		ns		
Rise Time	t <sub>r</sub>		4.5		ns	$V_{DD}$ =5V, $I_{D}$ =3.7A $R_{G}$ =6.2 $\Omega$ , $R_{D}$ =4.0 $\Omega$ (Refer to test circuit)	
Turn-Off Delay Time	t <sub>d(off)</sub>		20.5		ns		
Fall Time	t <sub>f</sub>		8		ns	(herer to test circuit)	
Total Gate Charge	Qg			27	nC	\\ 0.4\\\\\ 10\\	
Gate-Source Charge	Q <sub>gs</sub>			5	nC	V <sub>DS</sub> =24V,V <sub>GS</sub> =10V, I <sub>D</sub> =3.7A (Refer to test circuit)	
Gate Drain Charge	$Q_{gd}$			4.5	nC		
SOURCE-DRAIN DIODE							
Diode Forward Voltage (1)	V <sub>SD</sub>			0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> =3.7A, V <sub>GS</sub> =0V	
Reverse Recovery Time (3)	t <sub>rr</sub>		24.5		ns	T <sub>j</sub> =25°C, I <sub>F</sub> =3.7A, di/dt= 100A/μs	
Reverse Recovery Charge(3)	Q <sub>rr</sub>		19.1		nC		

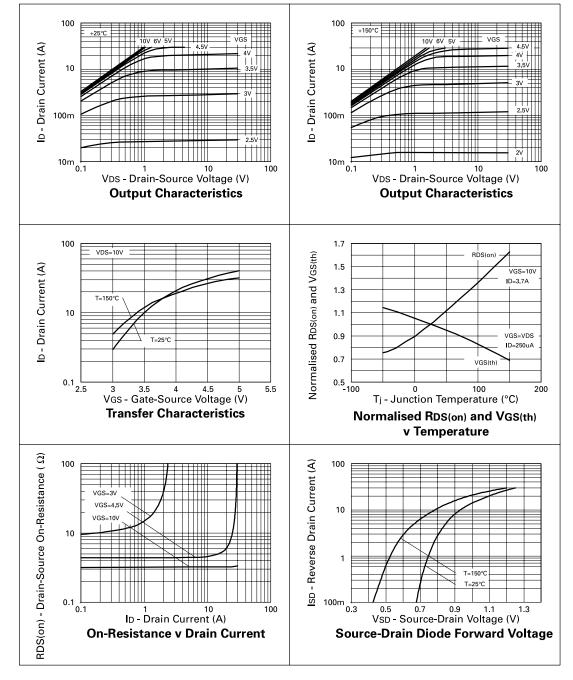
<sup>(1)</sup> Measured under pulsed conditions. Width=300 $\mu s.$  Duty cycle  $\leq\!2\%.$ 



<sup>(2)</sup> Switching characteristics are independent of operating junction temperature.

<sup>(3)</sup> For design aid only, not subject to production testing.

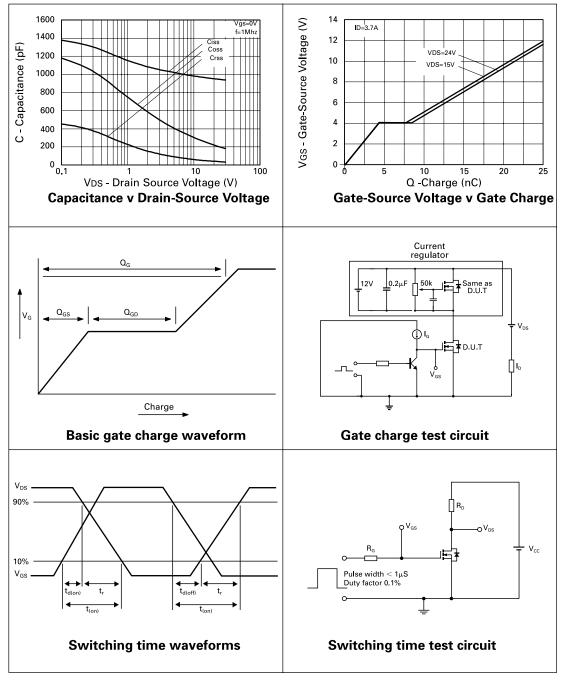
### **TYPICAL CHARACTERISTICS**



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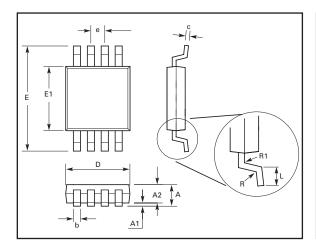
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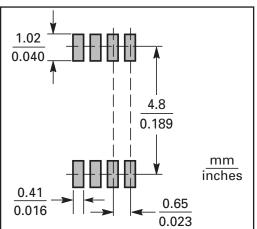




# **PACKAGE DETAILS**



### **PAD LAYOUT DETAILS**



# **PACKAGE DIMENSIONS**

DIM	Millimeters		Inches		
	MIN	MAX	MIN	MAX	
Α	0.91	1.11	0.036	0.044	
A1	0.10	0.20	0.004	0.008	
В	0.25	0.36	0.010	0.014	
С	0.13	0.18	0.005	0.007	
D	2.95	3.05	0.116	0.120	
е	0.65NOM		0.0256		
e1	0.331	NOM	0.0128		
Е	2.95	3.05	0.116	0.120	
Н	4.78	5.03	0.188	0.198	
L	0.41	0.66	0.016	0.026	
θ°	0°	6°	0°	6°	

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Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH	Zetex Inc	Zetex (Asia) Ltd	Zetex Semiconductors plc
Streitfeldstraße 19	700 Veterans Memorial Hwy	3701-04 Metroplaza Tower 1	Zetex Technology Park
D-81673 München	Hauppauge, NY 11788	Hing Fong Road, Kwai Fong	Chadderton, Oldham, OL9 9LL
Germany	USA	Hong Kong	United Kingdom
Telefon: (49) 89 45 49 49 0	Telephone: (1) 631 360 2222	Telephone: (852) 26100 611	Telephone (44) 161 622 4444
Fax: (49) 89 45 49 49	Fax: (1) 631 360 8222	Fax: (852) 24250 494	Fax: (44) 161 622 4446
europe.sales@zetex.com	usa.sales@zetex.com	asia.sales@zetex.com	hq@zetex.com

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